

Identification of degradation and manufacturing issues using multi-parameter mapping of organic solar cells

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Agenda

- Short introduction to NPL
- Challenges for organic solar cells
- Why mapping at different scales is important?
- Examples
 - Nanoscale photocurrent map
 - Nanoscale multiparameter
 - Microscale PL, Raman, Photocurrent
 - In-situ photocurrent mapping
- Final remarks

National Physical Laboratory - UK

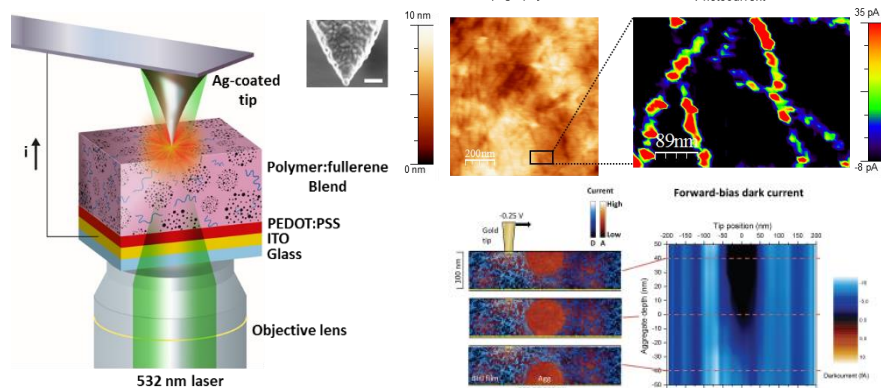
- UK's metrology institute established in 1900
- World-leading National Measurement Institute (Top 3 among ~100)
- 650 staff, 450 Graduate/PhD scientists - multidisciplinary



Photovoltaics at NPL

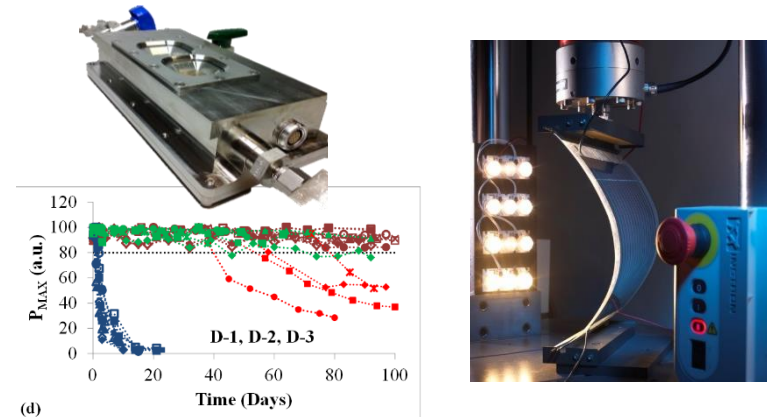
Nanoscale functional characterisation

Novel mapping methods & innovative modelling



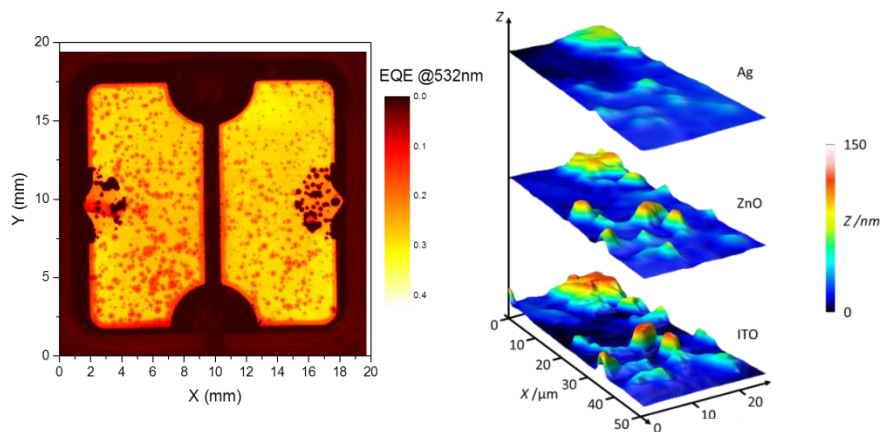
Stability (in-situ characterisation)

Novel in-situ characterisation & accelerated tests



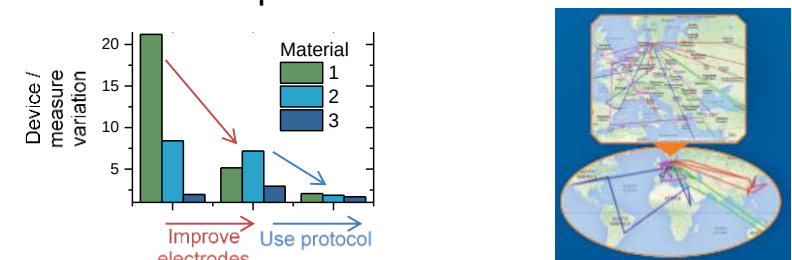
Quality control

Advanced defect characterisation



Standardisation

Measurement protocols International Round Robins



Collaborations:



Why Organic PV?

- Mechanical Flexibility / Weight reduction (e.g. 0.5 Kg/m²)
- Design Flexibility (color, transparency, shape...)
- Low environmental burden

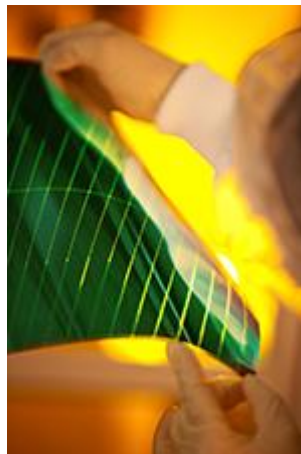


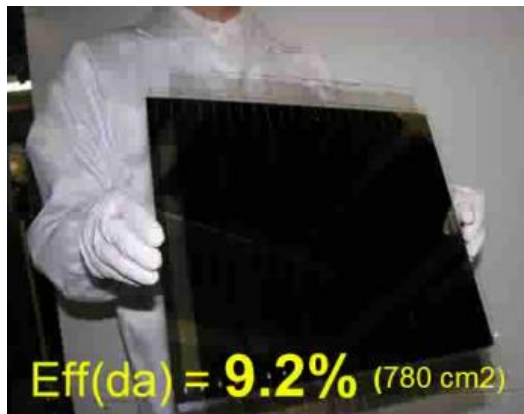
Image from Heliatek



Image from Heliatek

Recent examples from OPV industry

TOSHIBA
Leading Innovation >>>



JIS C 8938

Environmental and endurance test methods for amorphous solar cell modules
(corresponding to IEC 68-2-2, IEC 68-2-21, IEC 68-2-52)

Tests	Relative Reduction in PCE = $(PCE_{initial} - PCE_{after}) / PCE_{initial}$
(B-1) Dry heat test 85°C, 1000 hours	3%
(B-2) Damp heat test 85°C, 85%RH, 1000 hours	0%
(A-1) Thermal cycling test 90°C ↔ -40°C, 200 cycles	4%
(A-2) Temperature/humidity cycling test 85°C 85%RH ↔ -40°C, 10 cycles	2%
(A-5) Light soaking test 255 W/m ² (300~700 nm), 63°C, 500 hours	9.5%

 **BELECTRIC®**

African Union building
445 Belectric OPV solar
modules installed in 5 days!



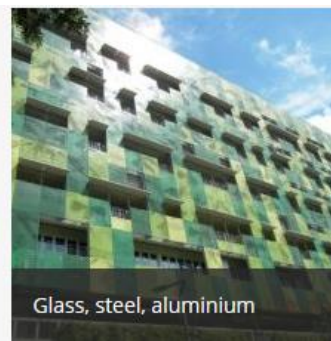
 **Heliatek®**
The future is light



Glass façade



Concrete façade

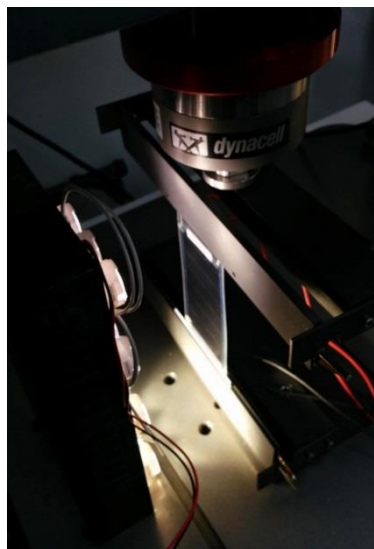
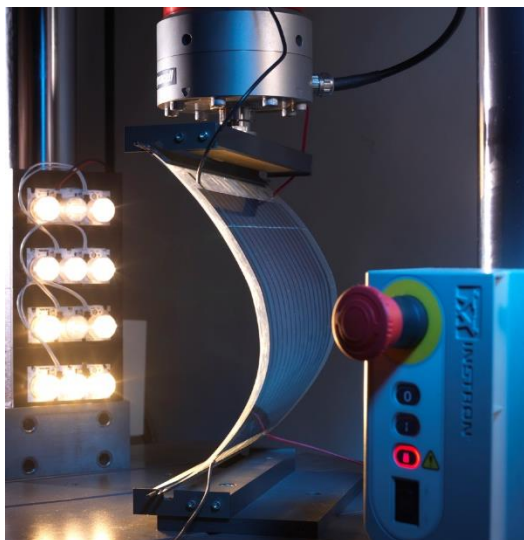


Glass, steel, aluminium



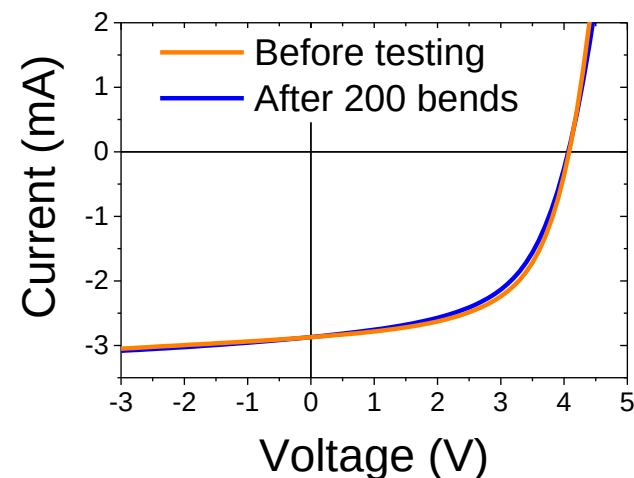
Glass car roof

Mechanically stable Organic Solar Cells



OPV module fabricated by Eight19 Ltd and characterised at NPL

Module was constantly illuminated at 10% of 1 sun intensity (100 W/m^2)



Current-voltage curves were measured in-situ after each bend.

Bend radius down to 25 mm.

Main challenges

OPV is not a single technology!

Hundreds of possible active layer materials

Different stack configurations (regular – inverted)

Numerous module design options

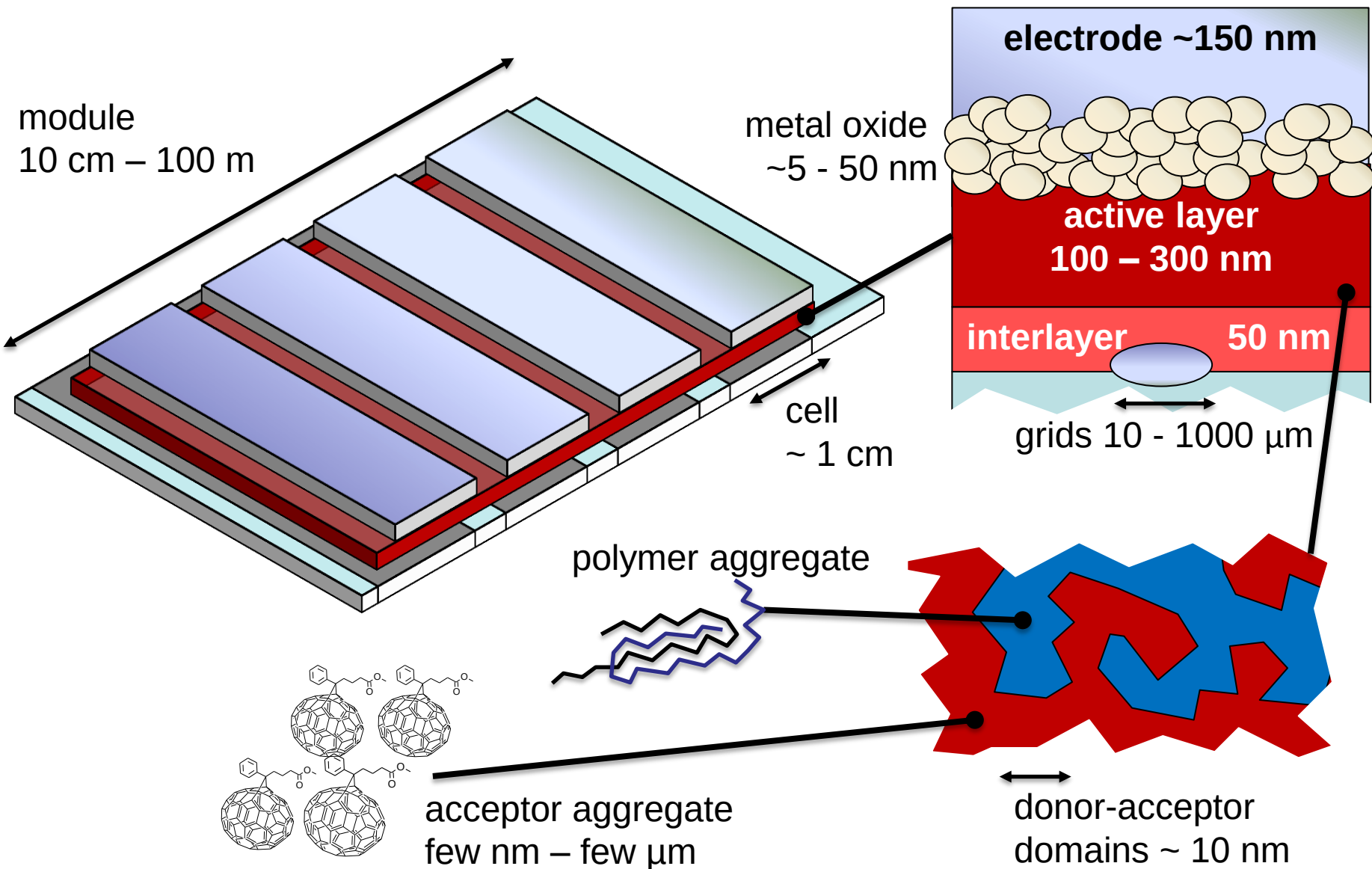
Many different deposition methods, substrates, interlayer materials...

Companies use proprietary materials

Key issues:

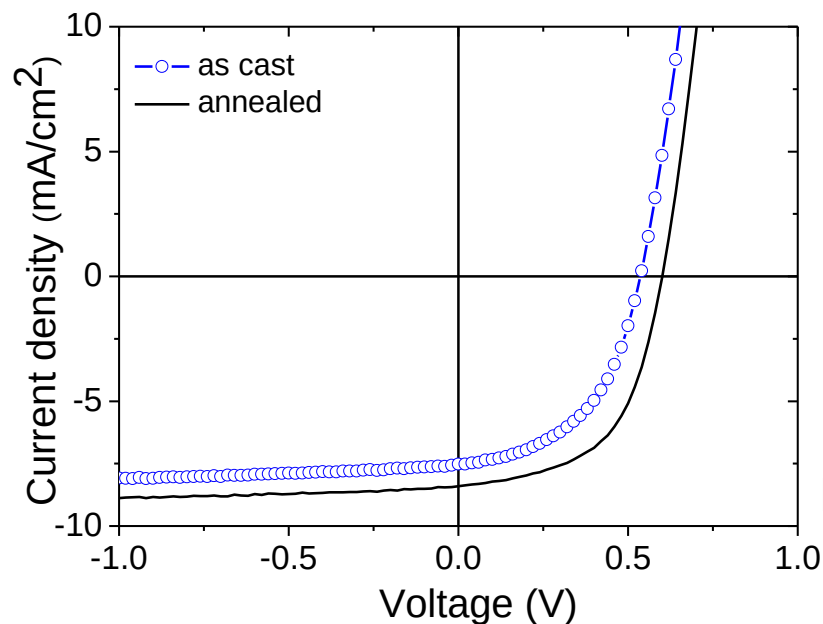
- Defect characterisation in multiple scales
- Identification of degradation mechanisms

Length scales of OPV

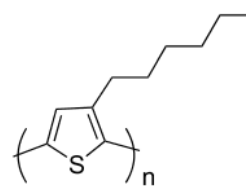


Example 1

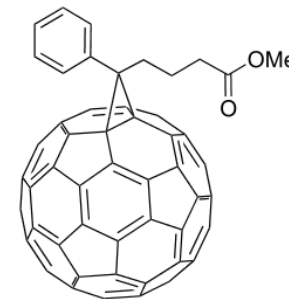
Nanoscale characterisation



Semiconductors



P3HT



PCBM

Increased efficiency upon thermal annealing

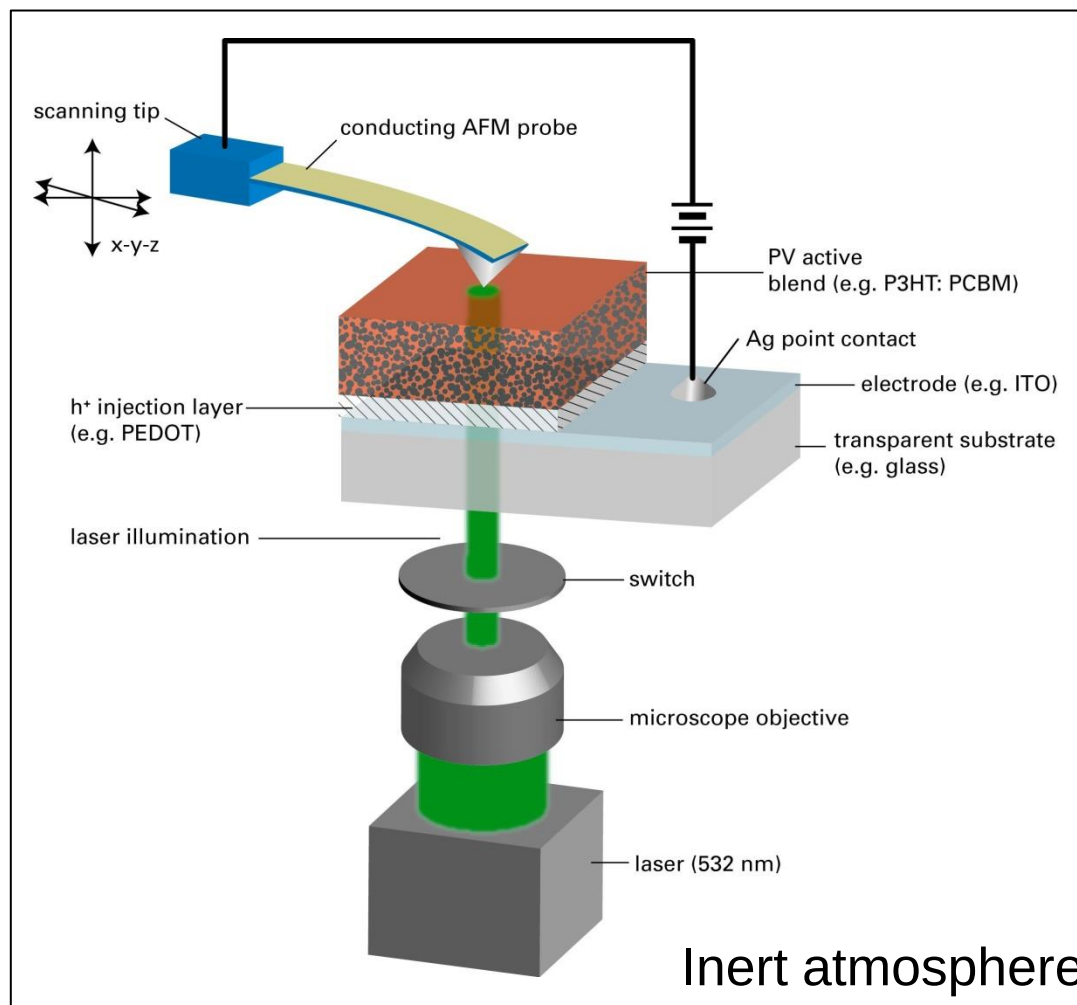
Why?

Sample: **P3HT Nanowires** : **PCBM**

Nanowire width ~ 20 nm

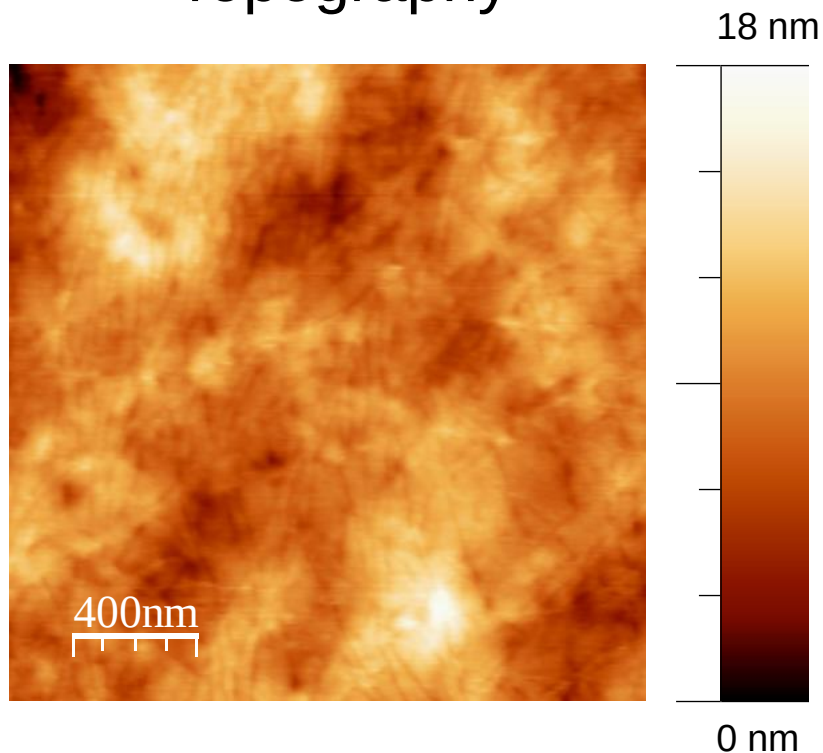
Example 1a

Photoconductive-AFM

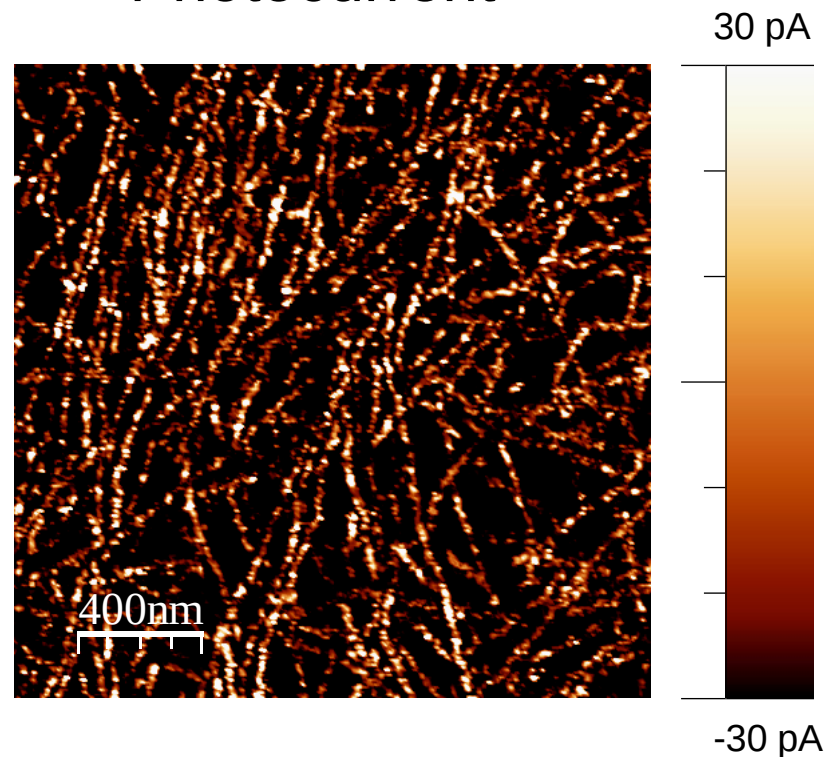


Photoconductive-AFM data on operating organic solar cell

Topography

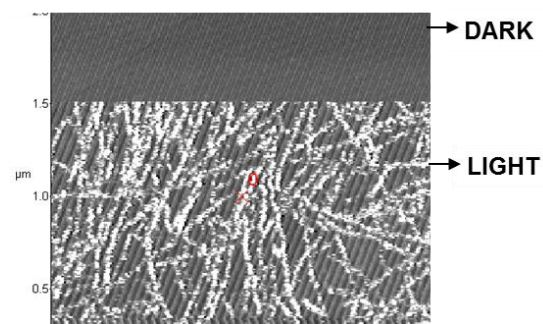


Photocurrent

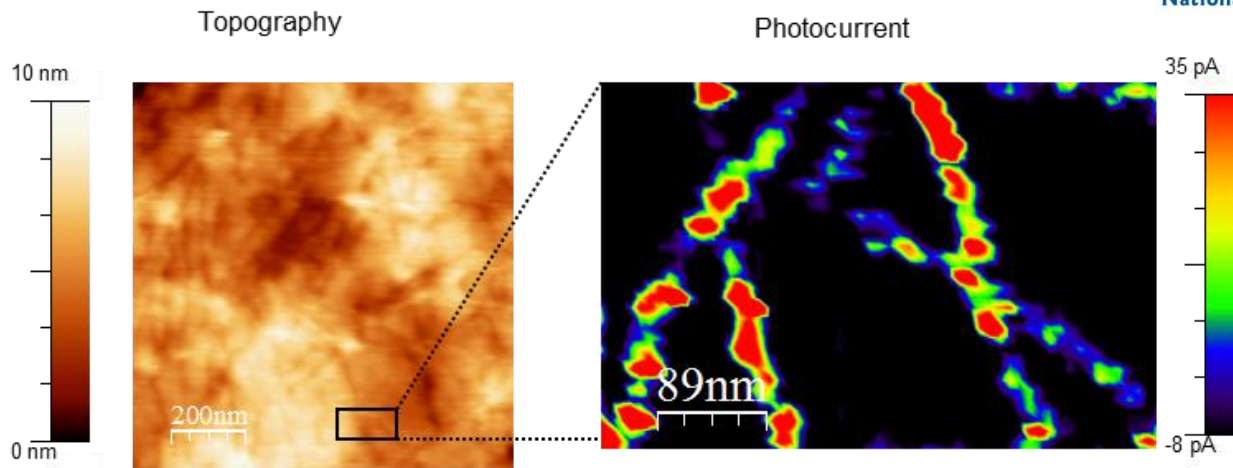


Topography: Very flat (RMS roughness ~ 2 nm)
Nanowires are embedded in the 80 nm thick film

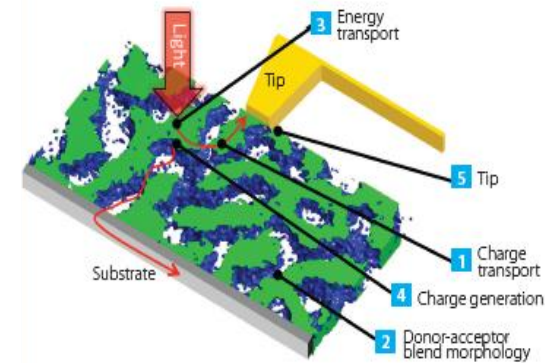
Real photocurrent



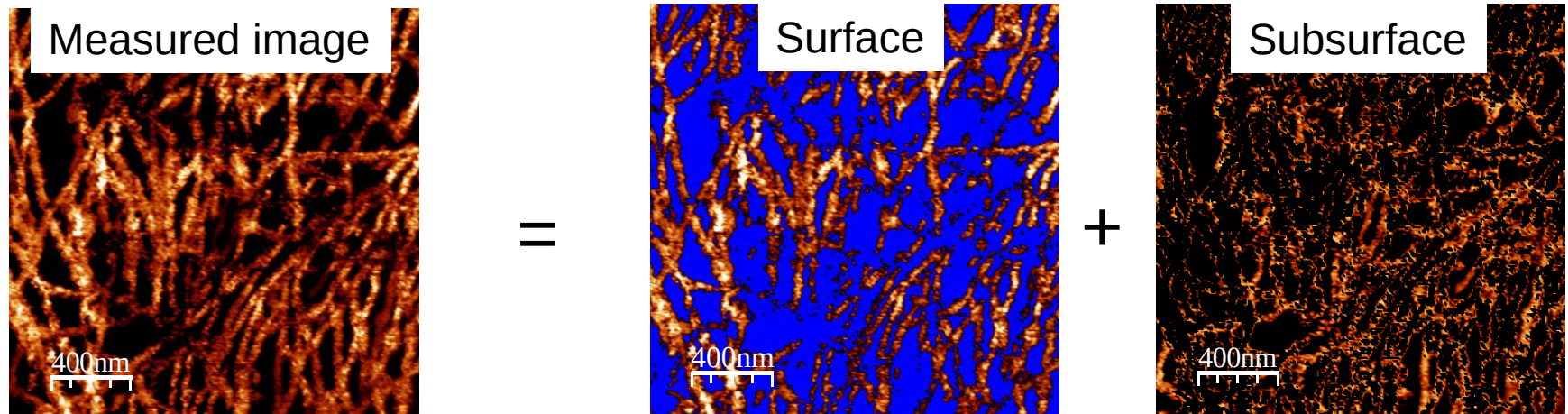
More than just surface information



Unique 3D simulation tool

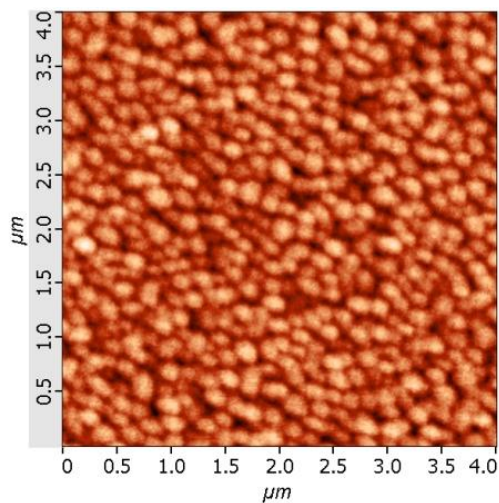


Surface and subsurface signal can be decoupled

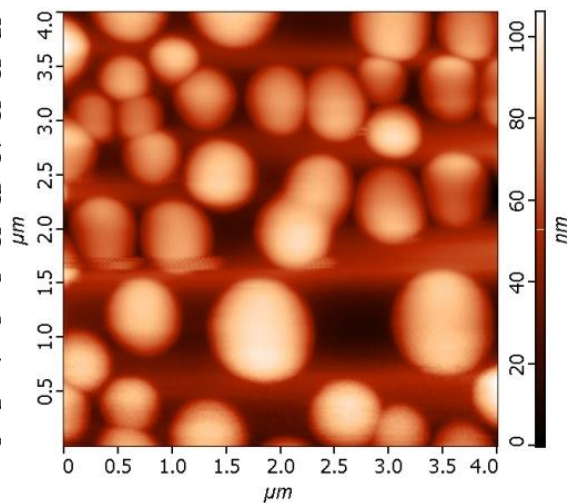


Example 2

What about samples where features are not obvious?

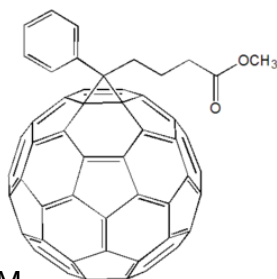
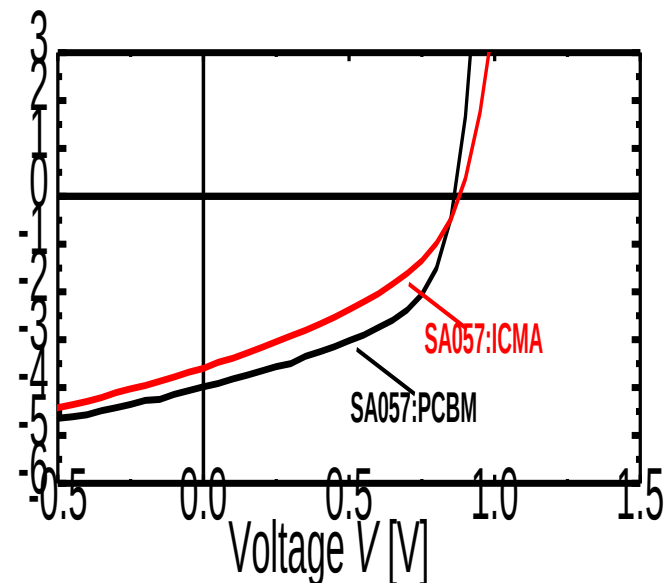


Si TPT-BT:PCBM

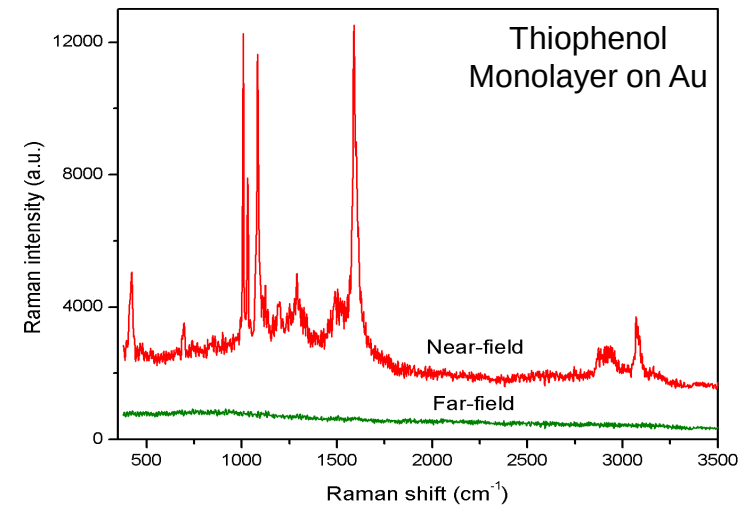
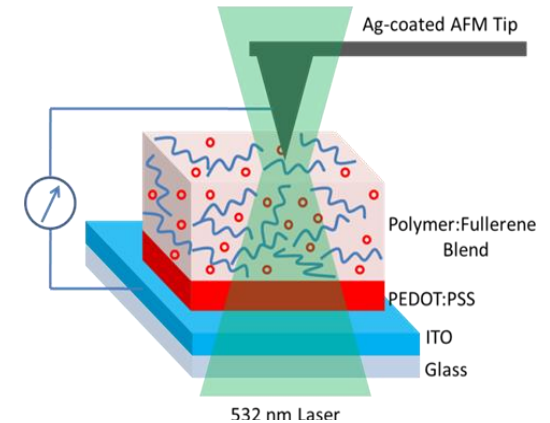
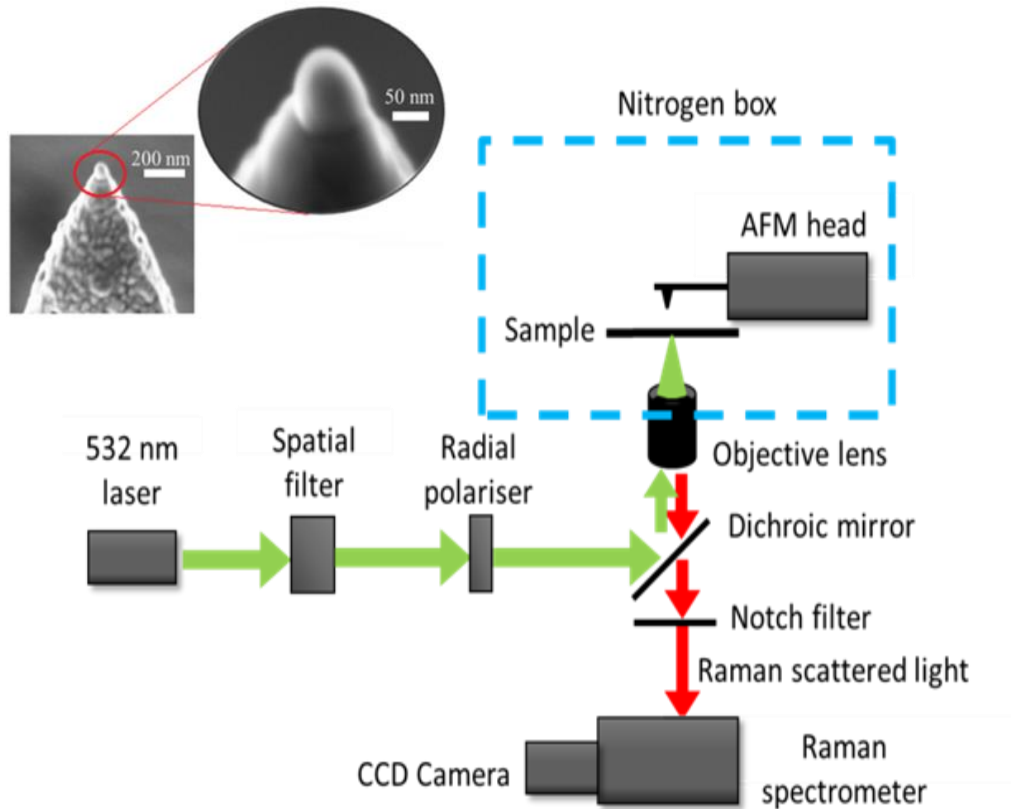


Si TPT-BT:ICMA

Current Density



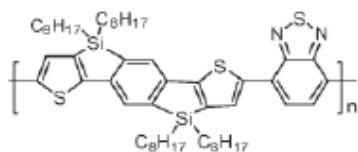
Tip-enhanced optical spectroscopy (Raman, Photoluminescence)



- Laser excites plasmon resonance
- Enhanced electromagnetic field close to the AFM tip

$$EF = \frac{(I_{Tip-in} - I_{Tip-out}) / A_{NF}}{I_{Tip-out} / A_{FF}}$$

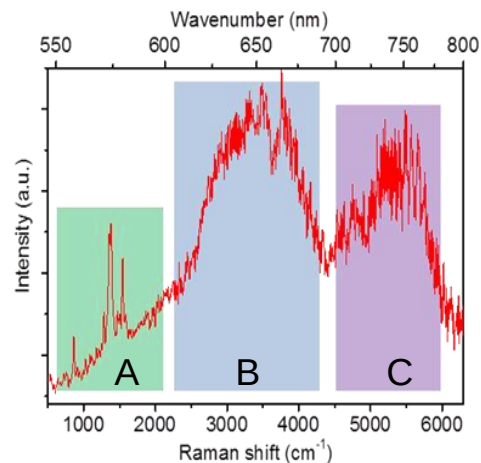
Tip-enhanced optical spectroscopy (TEOS)



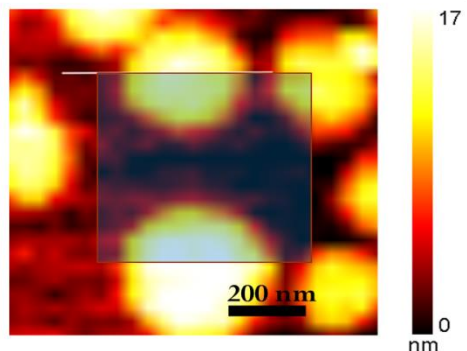
Si TPT-BT



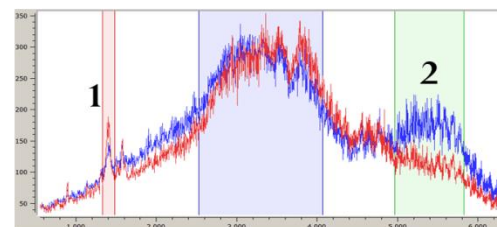
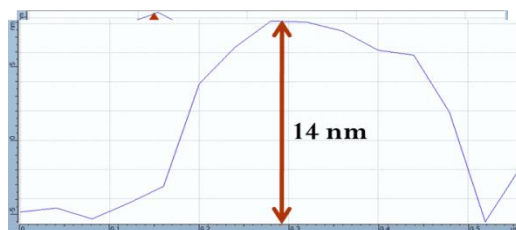
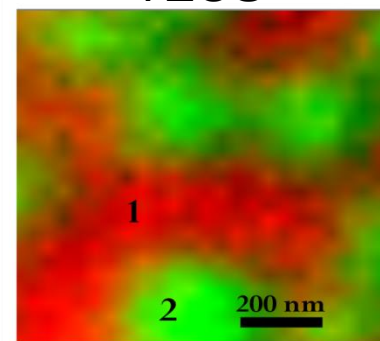
ICMA



Topography



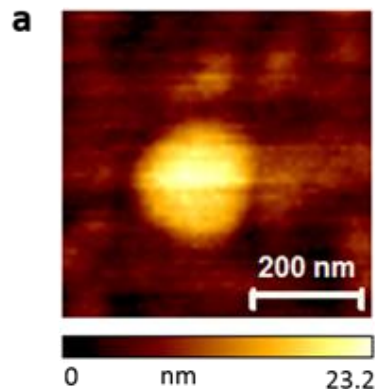
TEOS



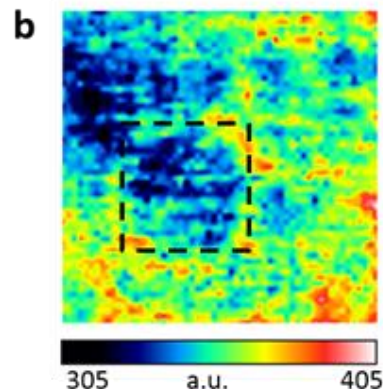
Green: Polymer Raman
Red: Fullerene PL

First simultaneous PC-AFM and TEOS

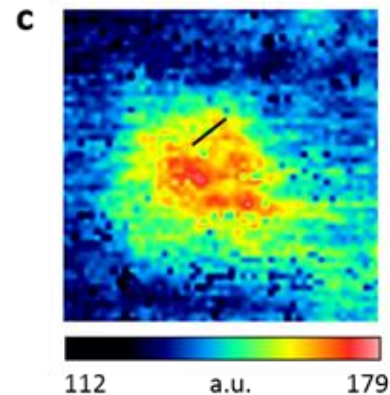
Topography



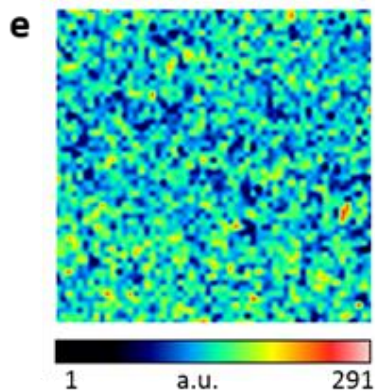
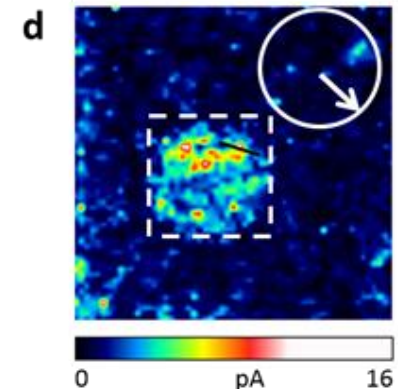
Polymer PL



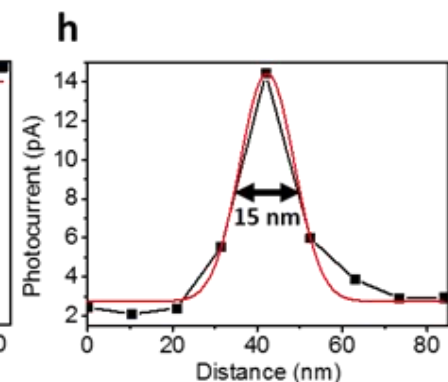
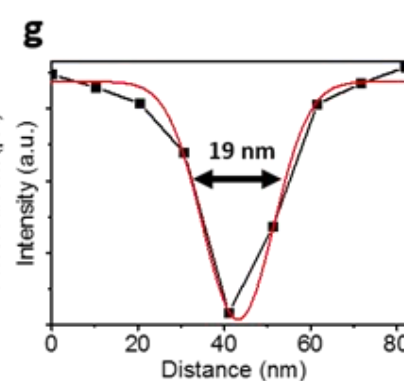
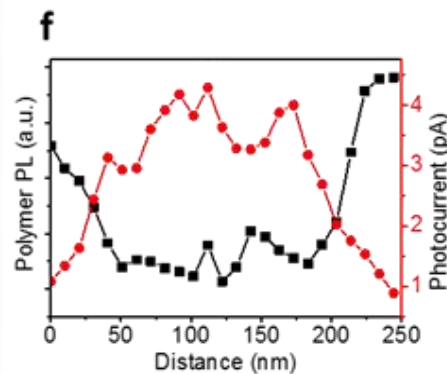
Fullerene PL



Photocurrent



Polymer Raman



Indication of measurement resolution

Example 2

Larger area multi-parameter mapping



Provides information about { Processing issues
Resistive losses over large areas
Degradation

Example of methods:

Photoluminescence
Raman
Photocurrent (LBIC)
Transmittance
Electroluminescence
Thermography

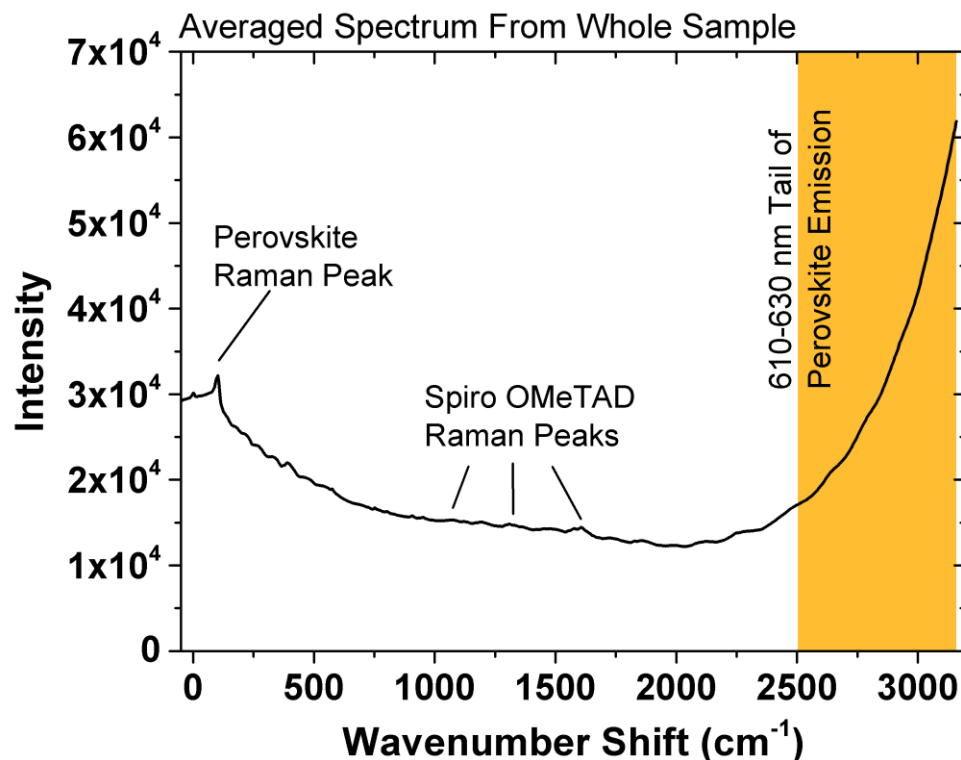
...

{ Can be combined in one experiment.

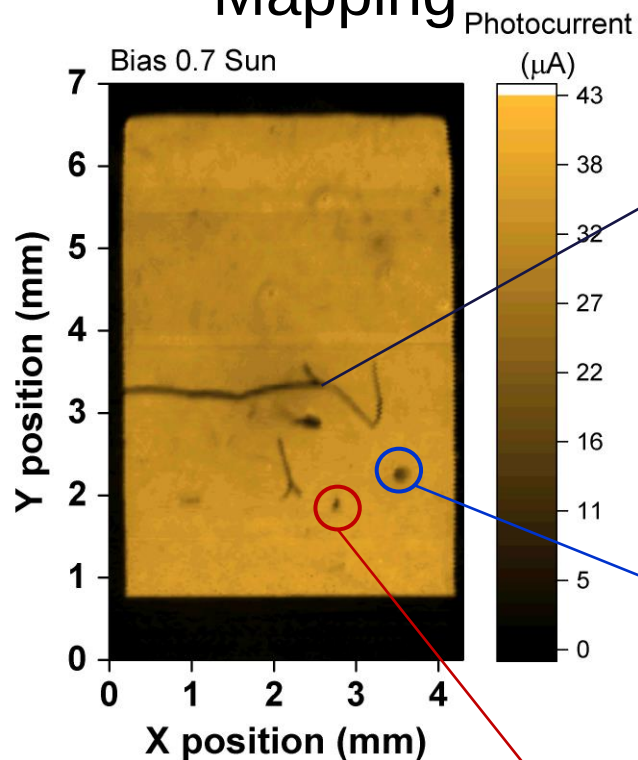
Example 2a: Manufacturing issues

Perovskite Solar Cell

Device Structure: glass/FTO/TiO₂/Mixed Halide Perovskite/SpiroOMeTAD/Gold

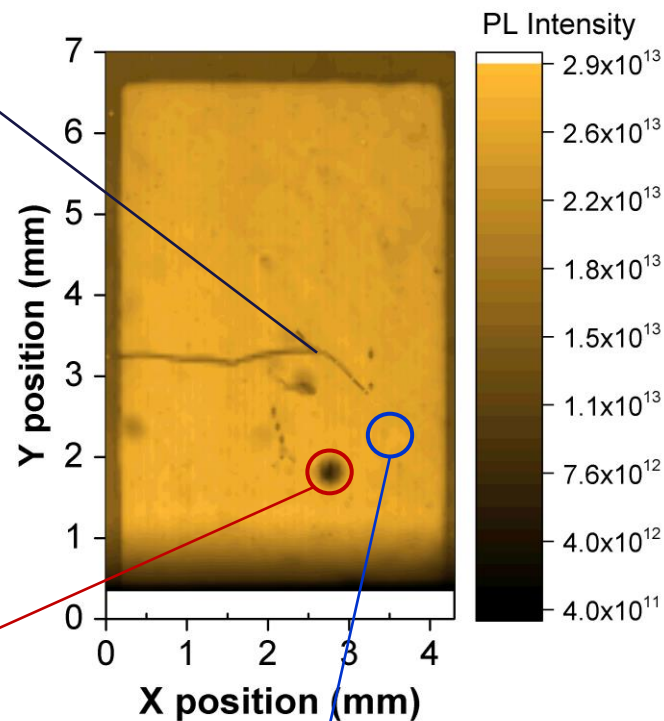


LBIC – Photocurrent Mapping



Scratch reduces photocurrent and PL intensity

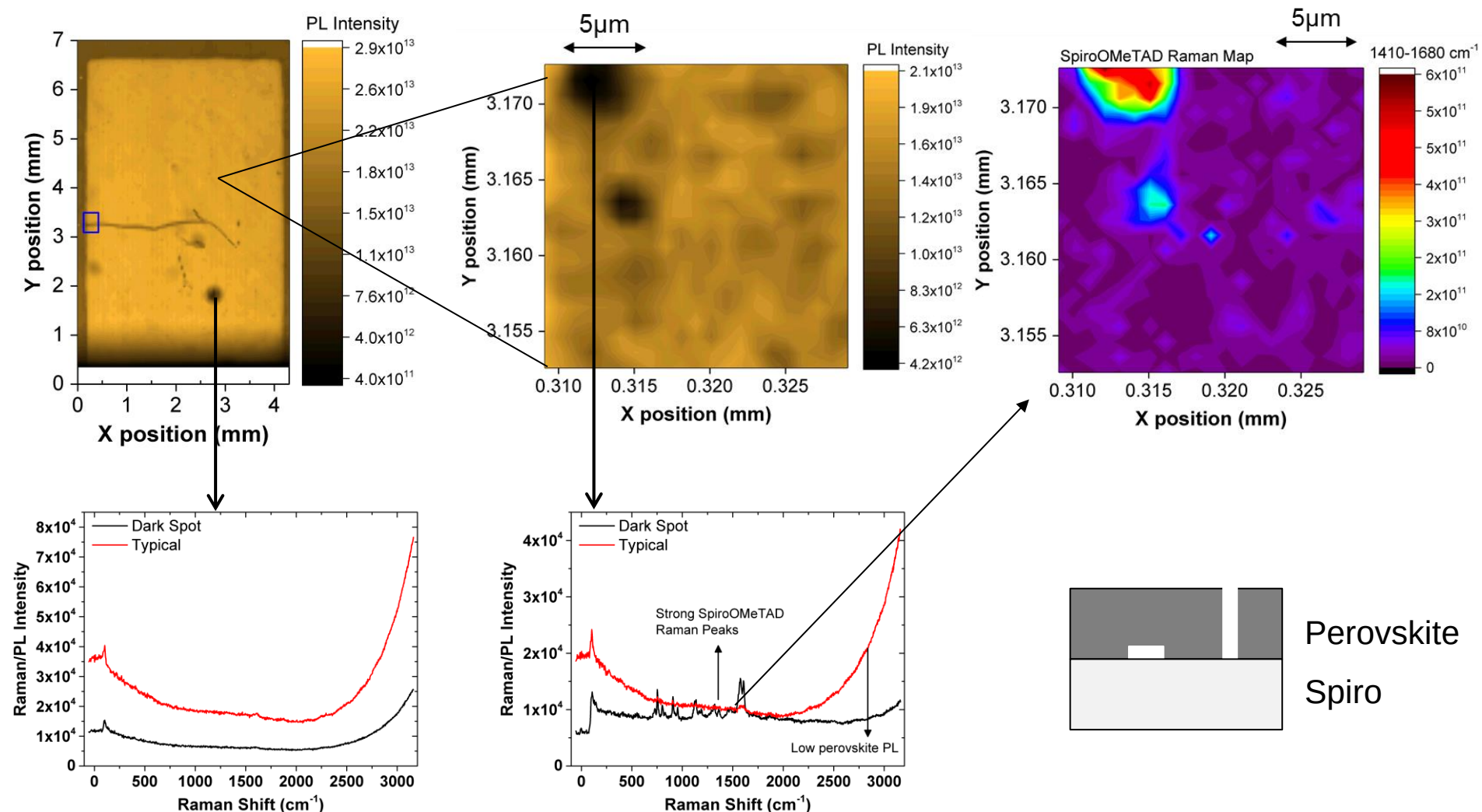
Perovskite PL Mapping



Loss of photocurrent matches reduced PL suggesting reduced active layer coverage.

Loss of photocurrent but no reduction in PL. Possible shunt.

micro PL/Raman Mapping



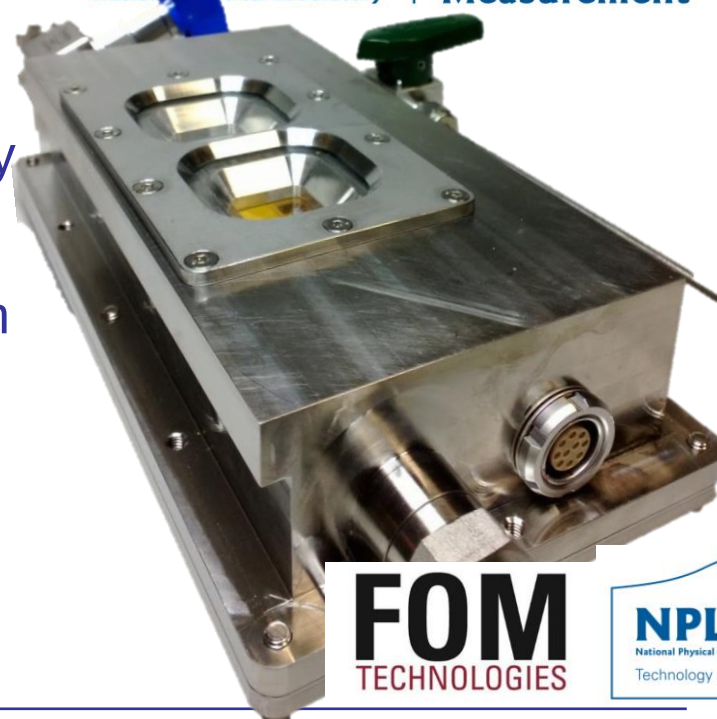
PL/Raman mapping can identify micrometre-scale defects: here the strong Raman signal from Spiro and low Perovskite PL suggest a hole in the perovskite layer capped with Spiro.

Example 2b: Degradation issues

NPL portable environmental chamber



- Simulates encapsulation environment
- Independent control of oxygen and humidity (selective stress testing)
- Automated testing and data acquisition with programmable environments
- *in-situ* characterisation using imaging techniques, μ -Raman, μ -PL, EQE, TPV/TPC etc.



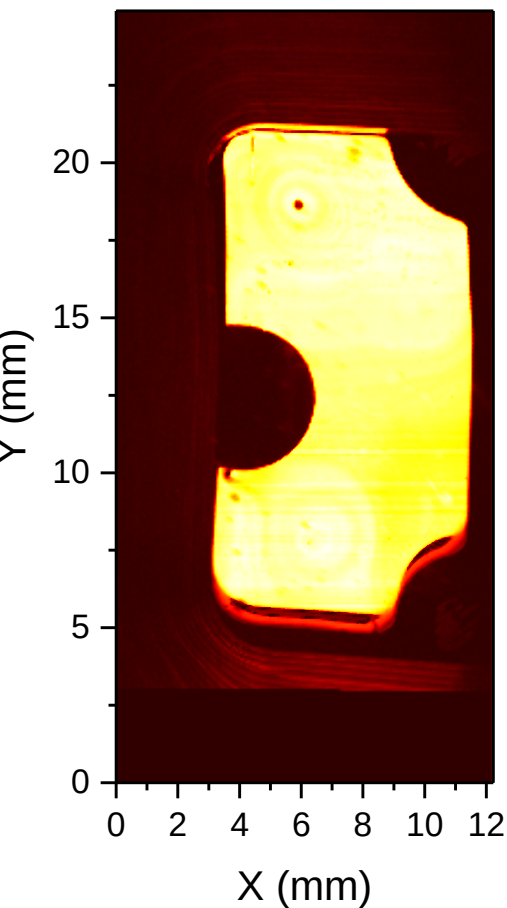
FOM
TECHNOLOGIES



Parameter	Range	Accuracy
Oxygen concentration	0.5 ppm to 21 % (>5 orders of magnitude)	± 10 % traceable
Humidity	1.0 ppm to ~10 % R.H. (>3 orders of magnitude)	± 20 % traceable
Temperature	+ 20 ° C to + 50 ° C	± 1 ° C
Light	AM 1.5 AAA Xe lamp solar simulator, traceable	
Balance gas	99.9999 % Nitrogen	

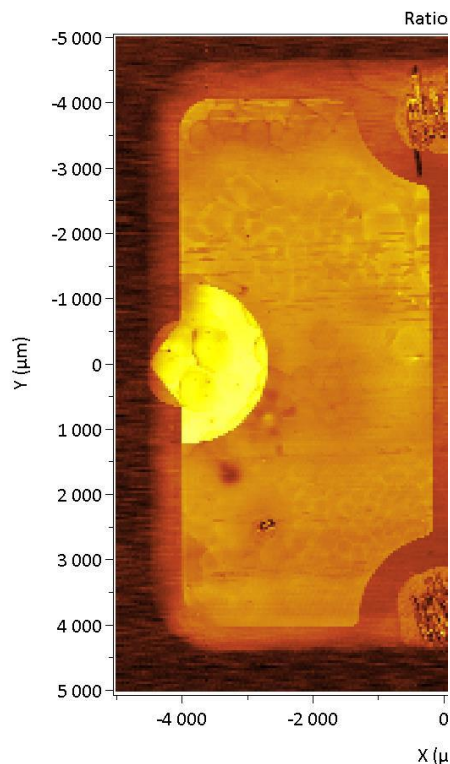
Complementary information

LBIC



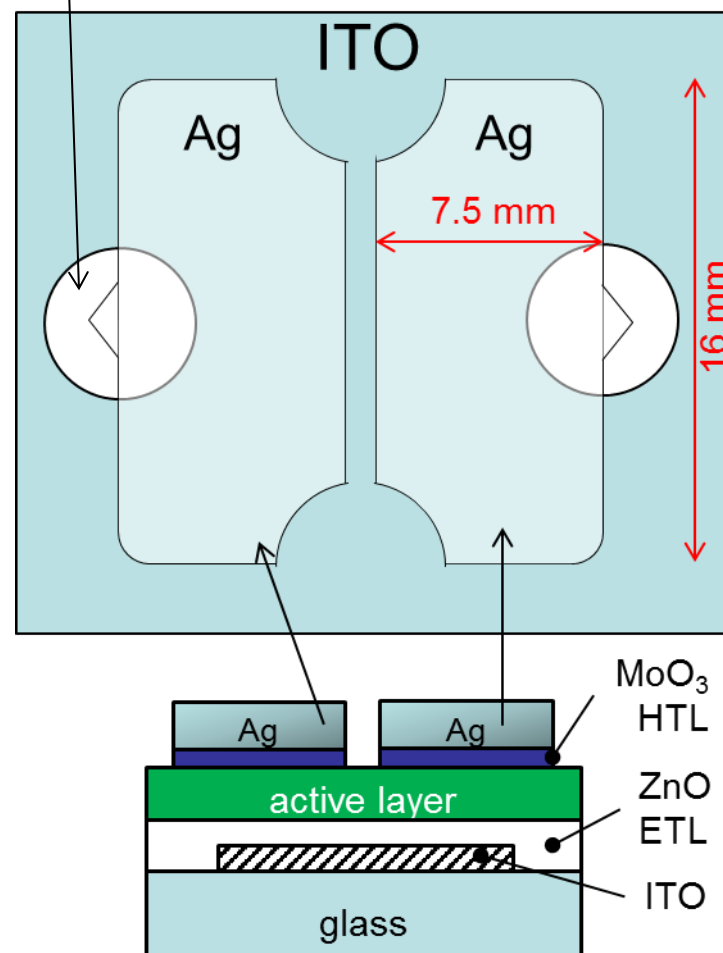
MoO₃ device
not exposed

PL



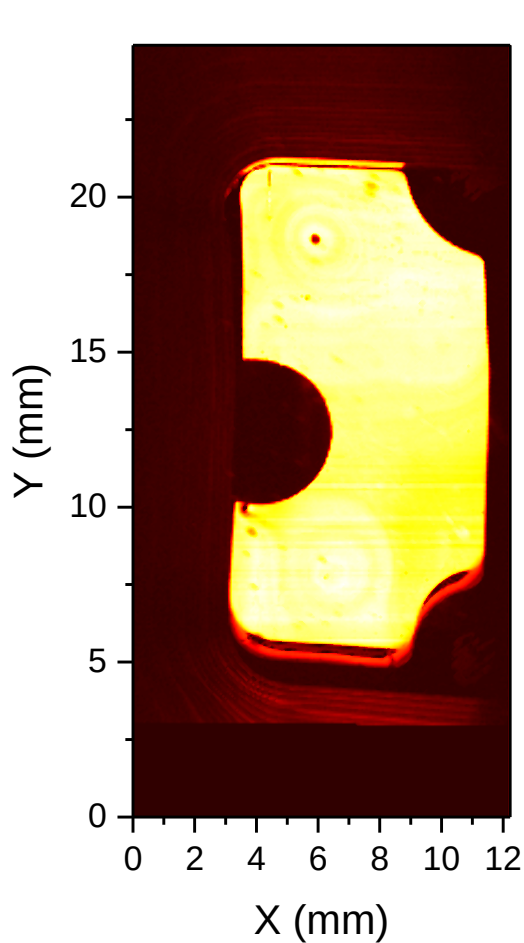
Micro-
Photoluminescence
mapping

gap in ITO

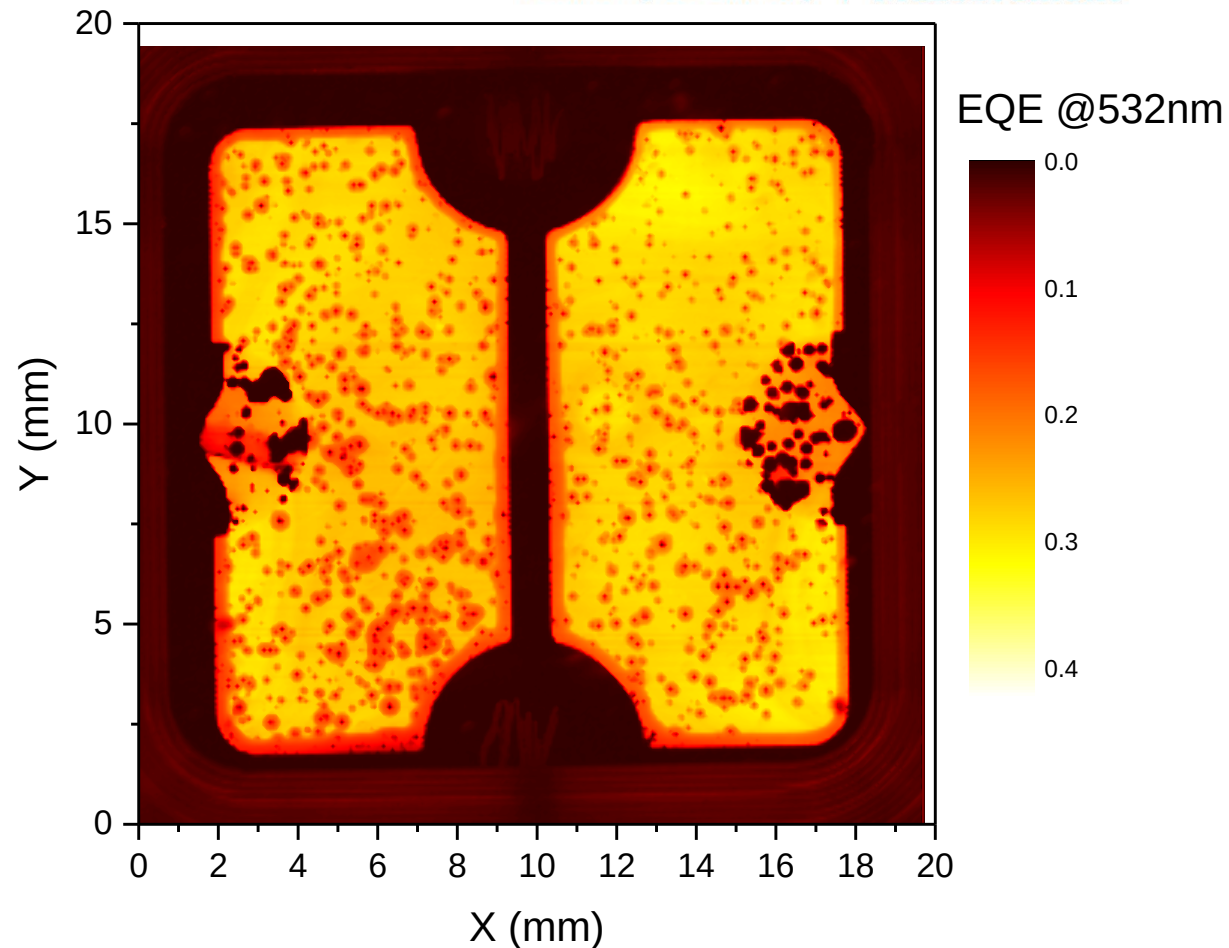


active area = 1 cm²

Photocurrent map (MoO_3)



In N_2
atmosphere



Unprotected device after long
term exposure to O_2

Final summary

- Still growing interest in OPVs. Key issues: defect characterisation in multiple scales / identification of degradation mechanisms
- Mapping/Imaging is key to provide insight into manufacturing and degradation issues
- Single methods are very limited. Combination of methods is preferred.
- Multiparameter (simultaneous) or in-situ characterisation avoids possible unwanted contamination/degradation between tests

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